SN54LS56, SN54LS57, SN74LS56, SN74LS57 FREQUENCY DIVIDERS

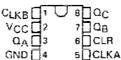
SDLS182

DECEMBER 1983-REVISED MARCH 1988

- 'LS56 Performs 50 to 1 Frequency Division (5 to 1, 5 to 1, and 10 to 1)
- 'LS57 Performs 60 to 1 Frequency Division (6 to 1, 5 to 1, and 10 to 1)
- Available in P or JG package (two P or JG Packages Fit in a Single 16-pin Socket)
- Maximum Clock Frequency 25 MHz Typical

SN54LS56, SN54LS57 . . . JG PACKAGE SN74LS56, SN74LS57 . . . JG OR P PACKAGE





FOR CHIP CARRIER INFORMATION, CONTACT THE FACTORY.

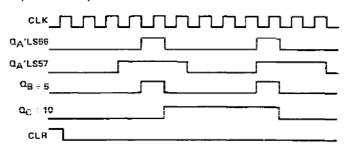
description

These frequency dividers are particularly useful in generating one second or one hour timing pulses from 50 Hz (European standard frequency) or 60 Hz (United States standard frequency), 50 to 1 frequency division is accomplished in the 'LS56 by connecting output Ω_A to input CLKB. 60 to 1 frequency division in the 'LS57 is accomplished in the same way. More universal capabilities are evidenced by the 25 MHz typical fmax and the almost limitless frequency division possibilities when used in cascade. Two 'LS56 packages may be interconnected to give frequency division of 2500 to 1, 625 to 1,100 to 1, etc. Two 'LS57 packages can be connected to generate frequency divisions of 3600 to 1, 1800 to 1, 900 to 1 etc.

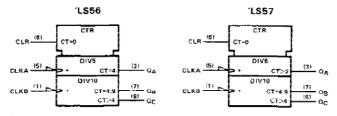
The 'LS56 and 'LS57 frequency dividers consist of three separate counters, A, B, and C on a single monolithic substrate. The A counter divides by 5 to 1 in the 'LS56 and by 6 to 1 in the 'LS57. The B counter divides by 5 to 1 in both devices and is internally tied to the C counter which divides by 2 to 1. The resulting C counter output is 10 to 1. Both the 'LS56 and 'LS57 feature a clear pin which is common to all three counters, A, B, and C. When the clear pin is low, the counters are enabled. When the clear is high, the counters are disabled and their outputs are set to a low-level.

All three counters, A, B, and C trigger on the high-to-low transition of the clock input. All output waveforms are symmetrical except for the 5 to 1 outputs (A and B of the 'LS56 and B of the 'LS57). See the output waveform drawings below.

input and output waveforms

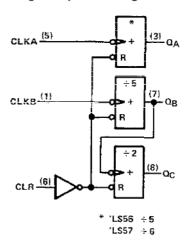


logic symbols†



[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)

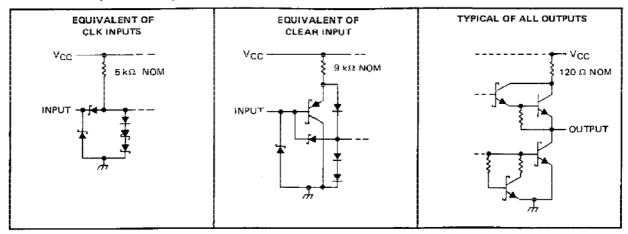


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SN54LS56, SN54LS57, SN74LS56, SN74LS57 FREQUENCY DIVIDERS

schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		7 V
Input voltage: CLR		7 V
CLKA, CLKB		5.5 V
Operating free-air temperature range:	\$N54LS'	55°C to 125°C
	SN74LS'	0°C to 70°C
Storage temperature range		65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

			SN54LS'			SN74LS'		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
Юн	High-level output current			-1			1	mΑ
loL	Low-level output current			8			16	mΑ
felock	Clock frequency	0		15	0		15	MHz
t _r , t _f	Rise and fall time of clock	"		50			50	ns
tw	Pulse width of clock or clear	30			30			ns
t _{su}	Clear inactive state set-up time	25			25			ns
TA	Operating free-air temperature	55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54LS'			SN74LS'				
		16	TEST CONDITIONS [†]			TYP\$	MAX	MIN	TYP#	MAX	UNIT
Vik		V _{CC} = MIN,	I _I = - 18 mA				- 1.5			- 1.5	V
Voн		V _{CC} = MIN, V _{IL} = MAX	V _{IH} = 2 V,	1 _{OH} = -1 mA	2.5	3.4		2.7	3.4		V
		Vcc = MIN,	V _{!H} = 2 V,	/ _{IH} = 2 V, I _{OL} = 8 mA		0.25	0.4	i	0.25	0.4	V
VOL	V _{IL} ≈ MAX	-	IOL = 16 mA	Ī		_		0.35	0.5		
	CLKA, CLKB	V _{CC} = MAX		V ₁ = 5.5 V			0.2			0.2	
Ч	CLR			V ₁ = 7 V			0.1			0.1	mA
CLKA, CLKB	CLKA, CLKB	V _{CC} = MAX, V _I = 2.7 V					80			80	
ΉΗ	CLR	VCC - MAX,	V -2.7 V				20			20	μΑ
112	CLKA, CLKB	V _{CC} = MAX,	CLR = 0 V,	V ₁ = 0.4 V			- 3.2			- 3.2	
	CLR						- 0,2			- 0.2	mA
os §		V _{CC} = MAX,	CLR = 0 V,	V0 = 0 V	- 20		- 100	- 20		- 100	mA
cc		V _{CC} = MAX,	See Note 2			17	30		17	30	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: ICC is measured by applying 4.5 V to the CLR pin with all other inputs grounded and the outputs open.

switching characteristics, VCC = 5 V, TA = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS			'LS56		'LS57			
					MIN	TYP	MAX	MIN	TYP	MAX	UNIT
fmax	CLKA	a _A			15	25		15	25		MHz
fmax	CLKB	Ω _B , Ω _C]		15	25		15	25		MHz
[†] PLH	21.175	0	}			8	15		8	15	пş
[†] PHL	CLKB	ΩB	A _L = 1 kΩ,	C _L = 30 pF		14	25	ļ	14	25	ns
[₹] PLH •	0.140					18	30		18	30	пѕ
tpHL*	CLKB	αc				24	35		24	35	ns
[†] PLH	CLKA		Ì			12	20		14	25	ns.
tPHL		QΑ				14	25		18	30	ns
[†] PHL	CLR	QΑ				17	30		17	30	กร
^t PHL	CLR	σe				17	30		17	30	ns
^t PHL	CLR	αc				17	30		17	30	ns

 \P Times measured from CLKB to output $Q_{\hbox{\scriptsize C}}$ are taken with output $Q_{\hbox{\scriptsize B}}$ unloaded. NOTE 3: Load circuits and voltage waveforms are shown in Section 1,

t All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time and the duration of the short-circuit should not exceed one second.

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